CP2K User Meeting 2016 — HowTo: Filter Matrix Diagonalisation REPEAT method for charge fitting

6th Feb. 2015

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Self-Consistent Field Calculation



Problem:

- Metallic systems: band-gap ~ 0.0 eV : conduction band contributing to ground state density
- In a Gamma point problem (CP2K):

$$n(\mathbf{r}) = \sum_{n} f_n(E_n) \Psi_n(\mathbf{r}) \Psi_n^*(\mathbf{r})$$

- Occupancy function is discontinuous (Fermi-Dirac function), a very small change in energy from a SCF step can lead to a jump in the electron charge density, as orbitals from the conduction band at near the Fermi-level gets either included or excluded.
 - Leads to instability in SCF calculations
- A common solution is to introduce smearing, $f_n(E_n)$ becomes continuous.
 - This requires the calculation of energy eigenvalues: not available to methods that directly minimises E with respect to density: (order N, or Orbital Transform methods).

Diagonalisation: Generalised Eigenvalue Problem



For Ground State we do not need full Hilbert space



- The density matrix projects any state into a space spanned by the lower energy eigenstates
- The smaller set of lower energy eigenstates give exact ground state energy (i.e. a smaller basis set)
- Unfortunately, we do not know the eigenstates a priori

We construct atomic orbitals in situ



$$\langle \phi_{ilpha} | \hat{H} | \phi_{jeta}
angle$$

 $\langle \tilde{\phi}_{i\mu} | \hat{H} | \tilde{\phi}_{j
u}
angle$

We try to construct a new basis set for each atom, based on the sub-molecular orbitals of the atom's neighbourhood.

Rayson and Briddon, Phys. Rev. B 80, 205104 (2009)

Construction of sub-system Hamiltonians











Atomic Density Matrices: Projectors for our new basis



n

Optimised for the atom within its environment

$$|\tilde{\psi}_n\rangle = \sum_{j\beta} C_{j\beta,n} |\phi_{j\beta}\rangle, \qquad ||\mathbf{R}_i - \mathbf{R}_j|| < r_{\mathrm{cut}}(i)$$

Still localised around position of atom i

Overall Scheme Of SCF Calculation



Filter matrix method input

&SCF &DIAGONALIZATION ALGORITHM FILTER_MATRIX &FILTER_MATRIX FILTER_TEMPERATURE 300000 AUTO_CUTOFF_SCALE 0.5 &END FILTER_MATRIX & END DIAGONALIZATION &PRINT &FILTER_MATRIX ON &END FILTER_MATRIX &END PRINT &END SCF

Accuracy



Basis set: DZVP-MOLOPT-SR-GTH

Pseudopotential: GTH-PADE-q3

Fermi-Dirac smearing: 300K

Computed on Cray XC30 (ARCHER), gfortran linked with Cray LibSci

Cutoff is defined as the ratio of the extent of the broadest primary basis function. The larger the cutoff the more accurate is the result, but also becomes more expensive quickly

Cost comparison



Computed on Cray XC30 (ARCHER), gfortran linked with Cray LibSci

Basis set: DZVP-MOLOPT-SR-GTH

Pseudopotential: GTH-PADE-q3

Fermi-Dirac smearing: 300K

Filter basis reduction: DZP to SZ

Cost comparison



Computed on Cray XC30 (ARCHER), gfortran linked with Cray LibSci Imel

Basis set: O and H TZV2P-GTH

Pseudopotential: GTH-PADE

Filter basis reduction: TZV2P to SZ

MD comparison



Basis set: O and H TZV2P-GTH

Pseudopotential: GTH-PADE

Initial temperature: 300K



Electrostatic Potential Derived Atomic Charges

- Used for classical forcefield or Monte Carlo simulations for large numbers of atoms
 - Treatment of electrostatic interactions still remains a challenge for transferable forcefields
 - We need an assortment of method to derive atomic charges in an interactive system
 - Electrostatic potential (ESP) derived charges results from calculation from static DFT calculation, by fitting atomic charges to reproduce the electronic static potential
 - In a standard ESP approach restraints and constraints are often required during the fitting process to make the atomic charges to have physically meaningful values. These approaches are referred to as RESP methods.

Electrostatic Potential Derived Atomic Charges

• In CP2K's RESP implementation: electron density of point charges are represented by gaussian functions with fixed width

$$n(\mathbf{r}) = \sum_{a} q_a \left(\frac{\alpha}{\pi}\right)^{\frac{3}{2}} \exp\left(-\alpha \|\mathbf{r} - \mathbf{R}_a\|^2\right)$$

• The classical static potential due to point charges are then given as the solution of the Poisson's equation:

$$V_{\text{RESP}}(\mathbf{r}) = \sum_{a} q_a \iiint d^3 \mathbf{r}' \frac{g_a(\mathbf{r}, \mathbf{R}_a)}{\|\mathbf{r} - \mathbf{r}'\|}$$

• We try to fit $V_{\text{RESP}}(\mathbf{r})$ w.r.t. the DFT static potential using the parameters q_a

Phys. Chem. Chem. Phys. 17,14307-14316 (2015)

Electrostatic Potential Derived Atomic Charges

 Fitting process involves the minimisation of the residual function:
 Restraints Constraints

$$R = \frac{1}{N} \sum_{k}^{N} (V_{\text{DFT}}(\mathbf{r}_k) - V_{\text{RESP}}(\mathbf{r}_k))^2 + \beta \sum_{j} (q_j - t_j)^2 + \lambda \sum_{j} q_j$$

- Restraints: *qa* should be preferably stay within a stated range, by introducing (quadratic) penalty functions
- Constraints: *q*^{*a*} must obey certain rules, such as the conservation of total charge, by using Lagrange multipliers

Phys. Chem. Chem. Phys. 17, 14307-14316 (2015)

REPEAT modification to fitting function

$$R = \frac{1}{N} \sum_{k}^{N} (V_{\text{DFT}}(\mathbf{r}_{k}) - V_{\text{RESP}}(\mathbf{r}_{k}))^{2} + \beta \sum_{j} (q_{j} - t_{j})^{2} + \lambda \sum_{j} q_{j}$$

$$R = \frac{1}{N} \sum_{k}^{N} (V_{\text{DFT}}(\mathbf{r}_{k}) - (V_{\text{RESP}}(\mathbf{r}_{k}) + \delta_{V}))^{2} + \beta \sum_{j} (q_{j} - t_{j})^{2} + \lambda \sum_{j} q_{j}$$

$$\delta_{V} = \frac{1}{N} \sum_{k}^{N} (V_{\text{DFT}}(\mathbf{r}_{k}) - V_{\text{RESP}}(\mathbf{r}_{k}))$$

- For periodic systems, the base level of static potential is ill-defined and arbitrary. It is the shape of the potential surface that matters.
- For REPEAT method, instead of fitting the value of the potential, we will only fit the variance (shape) of the electro-static surface. Coupled with spherical sampling, this leads to a more reasonable set of charges without the need of restraints.

J. Chem. Theory Comput. 5, 2866–2878 (2009)

REPEAT Input

&PROPERTIES &RESP # RESTRAIN_HEAVIES_TO_ZERO F USE_REPEAT_METHOD T STRIDE 2 &SPHERE SAMPLING AUTO_RMAX_SCALE 100.0 AUTO_RMIN_SCALE 1.0 AUTO VDW RADII TABLE UFF & END SPHERE SAMPLING &PRTNT &PROGRAM_RUN_INFO &END PROGRAM_RUN_INFO &END PRINT &END RESP & END PROPERTIES

&PROPERTIES &RESP USE REPEAT METHOD T STRIDE 2 &SPHERE_SAMPLING RMIN_KIND 1.964 Ma RMIN_KIND 2.503 C RMIN KIND 1.876 H RMIN_KIND 2.275 0 RMAX 60 & END SPHERE_SAMPLING &PRINT & PROGRAM RUN INFO &END PROGRAM_RUN_INFO & END PRINT & END RESP & END PROPERTIES

REPEAT Output

STARTING RESP FIT

Calculating charges using REPEAT method.					
Number of explicit constraints:			0		
Number of explicit restraints:			0		
Constrain total charge			Т		
Restrain heavy atoms			F		
Stride:		2	2 2		
Rmax [angstrom]:			60.00000		
Box min [angstrom]:	0.00000	0.00000	0.00000		
Box max [angstrom]:	26.17006	22.66394	20.84412		
Width of Gaussian charge distribution [angstrom^-2]:					
Number of potential fitting points found:					

RESP chai	raes:			
Type	Atom	Ι	Charge	
RECD	1	Ma	1 678470	
RESP	2	0	-0.964519	
RESP	3	C	0.482668	
RESP	4	С	-0.230431	
RESP	5	Н	0.185626	
RESP	6	0	-0.990872	
RESP	7	0	-0.783722	
RESP	8	0	-0.980735	
RESP	9	С	1.003359	
RESP	10	C	-0.367970	